

**Notice of References Cited**

Application/Control No.

10/529,767

Applicant(s)/Patent Under  
Reexamination  
HAYAKAWA, TAKESHI

Examiner

FRANKLIN S. ANDRAMUNO

Art Unit

2424

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,417,680	08-2008	Aoki et al.	348/333.05
*	B	US-7,228,061	06-2007	Mori et al.	386/95
*	C	US-7,237,029	06-2007	Hino et al.	709/227
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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